



2625

**IN THE UNITED STATES PATENT AND TRADEMARK OFFICE**

**RECEIVED**

**JUL 11 2003**

**Technology Center 2600**

Application of: Hamid K. Aghajan  
Assignee: Applied Materials, Inc.  
Atty. Dkt.: 006816 USA/PDC/EBI/OR  
Serial No.: 09/365,517 Filed: August 2, 1999  
Examiner: Sheela C. Chawan Group Art Unit: 2625  
Title: Two-Dimensional Scatter Plot Technique for Defect Detection

Commissioner for Patents  
P.O. Box 1450  
Alexandria, Virginia 22313-1450

Sir:

Transmitted herewith is a response to the outstanding Office Action and an Extension Petition (with authorization for payment of fee from a Deposit Account). No claims have been added, and no additional filing fee is required.

Date: July 3, 2003

Respectfully submitted,  
By Michael B. Einschlag  
Michael B. Einschlag  
Reg. No. 29,301  
(650) 949-2267  
25680 Fernhill Drive  
Los Altos Hills, California 94024

Enc. Response to Outstanding Office Action  
Extension Petition (with authorization for payment of fee from a Deposit Account)

**CERTIFICATE OF MAILING under 37 C.F.R. 1.8(a)**

I hereby certify that this correspondence is being deposited on July 3, 2003 with the United States Postal Service as first class mail, with sufficient postage, in an envelope addressed to Commissioner for Patents, P.O. Box 1450, Alexandria, Virginia 22313-1450.

Michael B. Einschlag  
Michael B. Einschlag

July 3, 2003  
Date of Signature